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Histamine. — Preliminary X-ray studies of the crystalline free base. Corrections. By A. C. ANDREWS, FRANK DECOU, *Department of Chemistry*, and R. DEAN DRAGSDORF, *Department of Physics, Kansas State University, Manhattan, Kansas, U.S.A.*

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In the paper by Andrews *et al.* (1961) the calculated d -spacing for the $24\bar{1}$ planes listed in Table 1 should be 2.521 Å. The length of the b axis should be one-half of that given in the paper, i.e., $b = 7.64$ Å. With the latter correction, all k indices should then be one-half those listed. The unit cell has a volume of 302.8 Å³ and contains two molecules.

In addition to the data presented in the paper, $hk0$

and $0kl$ precession photographs have been made. These showed systematic absences for $0k0$ when k is odd. The space group is then $P2_1$.

Reference

ANDREWS, A. C., DECOU, F. & DRAGSDORF, R. D. (1961). *Acta Cryst.* **14**, 1293.

Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the General Secretary of the International Union of Crystallography (D. W. Smits, Mathematisch Instituut, University of Groningen, Reithdiepskade 4, Groningen, The Netherlands).

Pittsburgh Diffraction Conference

The annual Pittsburgh Diffraction Conference will be held on 7, 8 and 9 November 1962 at the Mellon Institute, Pittsburgh, Pennsylvania. Sessions will be devoted to instrumentation and techniques, structures, metals and alloys, defect lattices and/or radiation damage, with a

special session on X-ray and electron-diffraction microscopy. Professor Dame Kathleen Lonsdale, F.R.S., of the Chemistry Department, University College, London, will be the guest speaker for the Thursday evening meeting. A placement service will be available. Further information can be obtained from W. H. Robinson, Carnegie Institute of Technology, Pittsburgh 13, Pa., U.S.A.

Book Reviews

Works intended for notice in this column should be sent direct to the Editor (A. J. C. Wilson, Department of Physics, University College, Cathays Park, Cardiff, Great Britain). As far as practicable books will be reviewed in a country different from that of publication.

X-ray Metallography. By A. TAYLOR. Pp. VIII + 993. New York: Wiley. 1961. Price 216s.

There are now several good books dealing with the application of X-ray diffraction procedures to metallurgical problems, but in 1945 there were only two available in English. One of these of course was Barrett, and the other was Dr Taylor's 'Introduction to X-Ray Metallography', battered copies of which are still in use in many metallurgical laboratories. This new book should thus be welcomed in the way one greets an old friend, whose mannerisms and foibles are already well appreciated. As is to be expected after fifteen years, there are some signs of middle aged spread, and the author has had to omit 'Introduction' from the title in view of the 993 pages to be found between the covers.

The style and general approach of 'X-Ray Metallography' will already be familiar to readers of the earlier book, but it should be emphasized that this is a completely new book and not a revised edition of the old. No knowledge of X-ray methods or of crystallography is assumed, and most results are developed from first principles. Metallurgical ideas and terminology are also frequently presented *ab initio*, and the author fulfills

his claim that the book is equally suitable for the X-ray crystallographer who wants to get a feeling for the metallurgical applications of his techniques. The later chapters of the book describe in considerable detail the ways in which X-rays are used for such diverse purposes as the determination of phase diagrams, the investigation of crystal perfection, the determination of textures, or the study of phase transformations. It would be easy to criticise the way in which some of the more advanced topics are handled, but most unfair to do so. No really important development seems to have been omitted; selecting almost at random, there are descriptions of X-ray diffractometry, neutron diffraction, electron-probe analysis, the focusing techniques of Guinier and Tennevin and of Lambot, Vassamillet and Dejae, Lang's method of diffraction microradiography, the work of Warren and Averbach on line broadening, and descriptions of numerous investigations on stacking faults, short range order, clustering, etc.

On the theoretical side, one feels that the treatment is a little pedestrian. The reciprocal lattice is introduced in a very sketchy manner, Fourier-transform theory is not used at all, and the space which could be spared for such topics as the theory of dislocations is too brief to